## Adsorption Configuration Changes and Reactions of  $N_2O$  on  $V(110)$  between 80 and 200 K

Won Hui Doh, Hyun Suck Jeong, and Chang Min Kim\*

Department o<sup>f</sup> Chemistry, Kyungpook Nationa<sup>l</sup> University, Daegu 702-701, Korea

(Received January 28, 2010; CL-100087; E-mail: cmk@knu.ac.kr)

Adsorption and reactions of  $N_2O$  on  $V(110)$  have been investigated. The  $N_2O$  molecule is adsorbed on  $V(110)$  through the terminal nitrogen atom at 80 K. The molecular axis of  $N_2O$  is tilted from the surface, and the tilt angle is greater than 55°. The adsorption configuration of  $N_2O$  changes in the temperature range of 80 to 120 K, and decomposition of  $N<sub>2</sub>O$  takes place to produce  $N_2$ .

The reaction of nitrogen oxides  $(NO<sub>x</sub>)$  on metal and metal oxide surfaces has been the subject of numerous surface science studies. Nitrogen oxides are major components of air pollution, and the catalytic reaction of  $NO<sub>x</sub>$  on solid surfaces is important in environmental chemistry. In surface science studies of  $NO<sub>x</sub>$ , nitric oxide (NO) has been most extensively studied.<sup>1</sup> In the process of the NO reaction on solid surfaces, formation and desorption of nitrous oxide  $(N_2O)$  has been frequently observed.<sup>2</sup> To better understand the surface reaction of NO, it is crucial to investigate the adsorption and reactions of  $N_2O$  on solid surfaces.

In the present study the adsorption and reactions of  $N_2O$ on V(110) have been investigated using X-ray photoelectron spectroscopy (XPS) and a near-edge X-ray absorption fine structure (NEXAFS) techniques. We will discuss the adsorption geometry change of  $N_2O$  on  $V(110)$  in the process of the  $N_2O$ reaction in the temperature range of 80 to 200 K.

The XPS and temperature-programmed desorption (TPD) experiments were carried out in an ultrahigh vacuum (UHV) system whose base pressure was lower than  $2 \times 10^{-10}$  Torr. The XPS spectra were recorded using a  $300 W$  Al K $\alpha$  X-ray source and a hemispherical analyzer (model VG Cram 2). The NEXAFS experiment was performed at the 2B1 beam line of the Pohang Accelerator Laboratory, Korea. NEXAFS spectra were obtained by measuring partial electron yield using a hemispherical electron energy analyzer. The V(110) crystal was purchased from Metal Crystals and Oxides and cleaned by using a standard procedure.  $N_2O$  was introduced to the analysis chamber using a leak valve.

TPD was utilized to investigate the desorption products from the surface reaction of  $N_2O$  on  $V(110)$ . Figure 1 shows TPD profiles from  $N_2O$  adsorbed on  $V(110)$  at 80 K. Exposure of  $N_2$ O was (a) 0.1 and (b) 1.0 L and the heating rate was  $3 K s^{-1}$ . When  $N_2O$  exposure is 0.1 L, the only desorption product is  $N_2$ (28 amu) and the maximum desorption temperature is 100 K. As the exposure of  $N_2O$  increases, 44 and 30 amu desorption features are observed in addition to the 28 amu feature. The intensity ratio of the 44 to 30 amu feature is very close to the fragmentation pattern of  $N_2O$  in the mass spectrometer, and both 44 and 30 amu features represent  $N_2O$  desorption. Maximum desorption temperatures of  $N_2$  and  $N_2O$  are very close, but  $N_2O$ desorption takes place over a wider temperature range. This result implies that  $N_2$  is desorbed from decomposition of  $N_2O$ in the temperature range of 80 to 200 K while  $N_2O$  desorption



**Figure 1.** TPD profiles from  $N_2O$  adsorbed on  $V(110)$  at 80 K. Exposure of  $N_2O$  was (a) 0.1 and (b) 1.0 L. Heating rate was  $3 \tilde{K} s^{-1}$ .



Figure 2. Change of N 1s XPS spectra of  $N_2O$  adsorbed on V(110) as a function of the surface temperature.

is from the molecularly adsorbed form. No desorption was observed at temperatures higher than 200 K.

The adsorption state of  $N_2O$  on  $V(110)$  was investigated by using XPS. Figure 2 shows the N 1s XPS spectra of  $N_2O$ adsorbed on V(110). Initial adsorption of N<sub>2</sub>O at 80 K on V(110) produces two XPS features at 402.1 and 405.9 eV. Two nitrogen atoms of  $N_2O$ ,  $N_t$  (terminal) and  $N_c$  (central), are in different chemical environments. Two XPS features at 402.1 and 405.9 eV correspond to the terminal  $(N_t)$  and central  $(N_c)$  nitrogen of

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 $N_2O$ , respectively. The binding energies of  $N_2O$  do not change as the surface coverage of  $N_2O$  increases.

The V(110) surface dosed by 1.0 L of N<sub>2</sub>O at 80 K was heated, and the change of the N 1s XPS features was investigated. As the surface temperature increases, nitrogen 1s binding energies of  $N<sub>2</sub>O$  shift to higher energies. At 200 K, N 1s binding energies of  $N_2O$  shift to 402.5 and 406.5 eV, and the intensity of the peaks substantially attenuated. The new feature at 397 eV corresponds to atomic nitrogen. This result indicates that both desorption and decomposition of  $N_2O$  take place in the temperature range of 80 to 200 K. Surface defects could be responsible for the decomposition of  $N_2O$  to produce atomic nitrogen on the surface. This observation agrees very well with the TPD results.

The shift of the binding at  $120K$  is not caused by the adsorption of  $N_2O$  at different adsorption sites or surface defects. The shift of XPS features was not observed when  $N_2O$  exposure was increased from 0.1 to 5.0 L. The shift of binding energy to higher values indicates stronger interaction between adsorbed  $N_2O$  and the surface; the charge transfer from  $N_2O$  to the surface upon adsorption on  $V(110)$ . The molecular orbitals of N<sub>2</sub>O are well-known<sup>3</sup> and the HOMO is the  $2\pi$  orbital. For the effective interaction of the N<sub>2</sub>O  $2\pi$  orbital with metal d orbitals, N<sub>2</sub>O should be oriented parallel to the surface. The shift of the binding energy in the temperature range of 80 to 120 K indicates that the adsorption geometry of  $N_2O$  on  $V(110)$  changes in this temperature range. Note that the binding energy shift of center nitrogen is greater than that of terminal nitrogen. This observation implies that the adsorption geometry of central nitrogen is more affected than that of terminal nitrogen upon heating.

The adsorption geometry of  $N_2O$  on  $V(110)$  was further investigated by utilizing nitrogen K-edge NEXAFS. Figure 3 shows nitrogen K-edge NEXAFS features of  $N_2O$  adsorbed on V(110). The surface was prepared by dosing  $1.0 L$  of N<sub>2</sub>O at 80 K. Curves (a) and (b) were obtained at 80 K, and Curve (c) was obtained after heating the surface to 200 K. The incident photon beam was 20° glancing to the surface for the spectrum (a), and the beam was normal to the surface for the spectra (b) and (c). The spectra were normalized to have the same edge jump. The N K-edge spectra of  $N_2O$  show two intense resonance features. They can be assigned to the transitions of 1s electrons of terminal and central nitrogen to the  $3\pi$  orbital (LUMO) of N2O. Two features at 400.0 and 403.8 eV correspond to terminal and center nitrogen, respectively.

Nitrogen K-edge NEXAFS spectra of N<sub>2</sub>O adsorbed on V(110) show angular dependency. The NEXAFS spectrum obtained with the incident photon beam normal to the surface shows stronger resonance for the transition of N 1s electrons to the  $3\pi$  orbital of N<sub>2</sub>O. Notice that the  $3\pi$  orbital is oriented perpendicular to the molecular axis of  $N_2O$ . This observation clearly indicates that the  $N_2O$  molecule adsorbed on  $V(110)$  at 80 K is tilted from the surface. We are not going to calculate the exact adsorption angle simply based on the NEXAFS results, but we can estimate that the angle between the molecular axis of  $N<sub>2</sub>O$  and the surface should be greater than 55 $^{\circ}$ .

The  $N_2O$  molecule can be attached to the metal surface through terminal  $(N_t)$  or central  $(N_c)$  nitrogen. There have been efforts to determine which nitrogen atom of  $N_2O$  is bonded to the surface based on the relative intensities of terminal  $(N<sub>t</sub>)$ and central (N<sub>c</sub>) nitrogen  $\pi^*$  resonance features of NEXAFS.<sup>4</sup> However, controversial results have been reported. In the case of



**Figure 3.** NEXAFS features of  $N_2O$  adsorbed on V(110). The surface was prepared by exposing  $V(110)$  to 1.0 L of N<sub>2</sub>O at 80 K. The spectrum (a) was recorded with the photon beam glancing to the surface by  $20^{\circ}$  while the spectrum (b) was measured at normal incident of the photon beam. The spectrum (c) was obtained after heating the surface to 200 K.

 $N_2$ O on V(110), the N<sub>2</sub>O molecule is tilted on V(110). The N<sub>2</sub>O molecule should be bent for the adsorption through the central nitrogen atom in the tilted geometry. Adsorption-induced bending of  $N_2O$  is well known,<sup>5</sup> but the molecule should be bent significantly to maintain the tilting angle, 55°, between the N–N bond and the surface. We conclude that the  $N_2O$  molecule is adsorbed on  $V(110)$  through the terminal  $(N_t)$  nitrogen atom. At 200 K, the N 1s NEXAFS feature is significantly attenuated but does not show strong angular dependency. This observation shows that the adsorption geometry and the molecular structure of N2O are changed.

In summary,  $N_2O$  is adsorbed on  $V(110)$  through the terminal nitrogen atom at 80 K. In the temperature range of 100 to 200 K, the adsorption geometry of  $N<sub>2</sub>O$  changes, which results in stronger interaction between the central nitrogen atom and the surface. Desorption of  $N_2$  takes place in this temperature range.

This work was supported in part by Grant No. R01-2006- 000-10230-0 (2006) from the Korea Science and Engineering Foundation (KOSEF).

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